

Automotive MOSFET

OptiMOS™ 6 Power-Transistor







Features

- OptiMOS[™] power MOSFET for automotive applications
- N-channel Enhancement mode Normal Level
- Extended qualification beyond AEC-Q101
- PPAP Capable
- Enhanced electrical testing
- Robust design
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- RoHS compliant
- 100% Avalanche tested



General automotive applications.

Product Validation

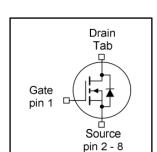
Qualified for automotive applications. Product validation according to AEC-Q101.

Product Summary

V_{DS}	150	V
R _{DS(on)}	3.8	mΩ
I _D (chip limited)	170	А

Туре	Package	Marking
IAUTN15S6N038	PG-HSOF-8-1	6N15N038





IAUTN15S6N038



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Maximum Ratings

at $T_j = 25$ °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	V _{GS} = 10 V, Chip limitation ^{1,2)}	170	А
		V _{GS} = 10 V, DC current	170	
		$T_a = 100$ °C, $V_{GS} = 10$ V, R_{thJA} on $2s2p^{2,3)}$	24	
Pulsed drain current ²⁾	I _{D,pulse}	$T_{\rm C}$ = 25°C, $t_{\rm p}$ = 100 μ s	601	1
Avalanche energy, single pulse ²⁾	E _{AS}	I _D = 85 A	285	mJ
Avalanche current, single pulse	I _{AS}	-	170	А
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P _{tot}	T _C = 25°C	263	w
Operating temperature	T _j	-	-55 +175	°C

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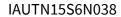
Thermal Characteristics²⁾

Parameter	Cumbal	Conditions	Values			11
Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Thermal resistance, junction - case	R_{thJC}	-	_		0.57	K/W
Thermal resistance, junction - ambient ³⁾	R_{thJA}	-	-	15.0	-	

Electrical Characteristics

at T_i=25 °C, unless otherwise specified

Parameter	Comple - I	Sumbal Sanditions	Values			
	Symbol	Conditions	min.	typ.	max.	Unit
Static Characteristics						
Drain-source breakdown voltage	V _{(Br)DSS}	$V_{GS} = 0 \text{ V},$ $I_D = 1 \text{ mA}$	150	-	-	V
Gate threshold voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 166 \mu\text{A}$	3	3.5	4	
		$V_{DS} = 120 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 25^{\circ}\text{C}$	-	_	1	μΑ
Zero gate voltage drain current	/ _{DSS}	$V_{DS} = 120 \text{ V}, V_{GS} = 0 \text{ V},$ $T_j = 100^{\circ}\text{C}^{2j}$	-	_	100	
Gate-source leakage current	I _{GSS}	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	100	nA
Dusing assumed an about a majesta and		$V_{GS} = 8 \text{ V}, I_D = 43 \text{ A}$	-	3.7	4.8	mΩ
Drain-source on-state resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 85 \text{ A}$	-	3.3	3.8	
Gate resistance ²⁾	R _G	-	-	1.0	-	Ω





Parameter	Symbol Conditions	Values			11:4:4		
		min.	typ.	max.	Unit		
Dynamic Characteristics ²⁾							
Input capacitance	C iss		_	4760	6200	pF	
Output capacitance	C oss	$V_{GS} = 0 \text{ V}, V_{DS} = 75 \text{ V}, f = 1 \text{ MHz}$	_	1370	1780		
Reverse transfer capacitance	C _{rss}		-	27	40		
Turn-on delay time	t _{d(on)}		-	17	-	ns	
Rise time	t _r	$V_{DD} = 75 \text{ V}, V_{GS} = 10 \text{ V},$ $I_{D} = 85 \text{ A}, R_{G} = 3.5 \Omega$	_	36	-		
Turn-off delay time	t _{d(off)}		_	26	-		
Fall time	t _f		_	33	-		

Gate Charge Characteristics2)

Gate to source charge	Q _{gs}		-	26	33	nC
Gate to drain charge	Q _{gd}	$V_{DD} = 75 \text{ V}, I_{D} = 85 \text{ A},$	_	17	25	
Gate charge total	Qg	$V_{DD} = 75 \text{ V}, I_{D} = 85 \text{ A},$ $V_{GS} = 0 \text{ to } 10 \text{ V}$	-	67	88	
Gate plateau voltage	V _{plateau}		-	5.4	-	V

Reverse Diode

Diode continuous forward current ²⁾	Is	T _C = 25°C	ı	ı	170	А
Diode pulse current ²⁾	I _{S,pulse}	$T_{\rm C} = 25^{\circ}{\rm C}, t_{\rm p} = 100 \mu{\rm s}$	ı	ı	601	
Diode forward voltage	V _{SD}	$V_{GS} = 0 \text{ V}, I_F = 85 \text{ A}, T_j = 25^{\circ}\text{C}$	ı	0.9	1.0	V
Reverse recovery time ²⁾	t _{rr}	$V_R = 75 \text{ V}, I_F = 50 \text{ A}$	-	33	50	ns
Reverse recovery charge ²⁾	Q _{rr}	$di_F/dt = 100 A/\mu s$	ı	16	32	nC

 $^{^{1)}}$ Practically the current is limited by the overall system design including the customer-specific PCB.

²⁾ The parameter is not subject to production testing – specified by design.

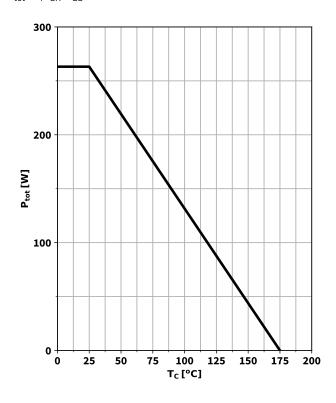
³⁾ Device on 2s2p FR4 PCB defined in accordance with JEDEC standards (JESD51-5, -7). PCB is vertical in still air.



Electrical characteristics diagrams

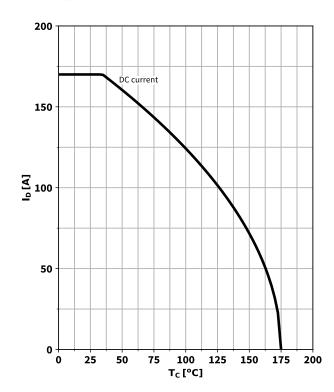
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$



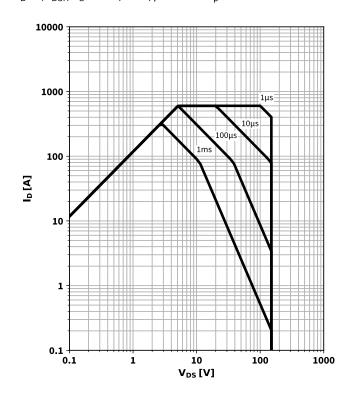
2 Drain current

$$I_{\text{D}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$



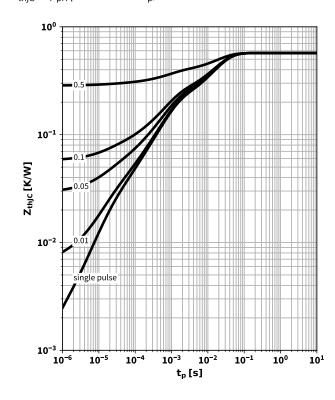
3 Safe operating area

$$I_{\rm D}$$
 = f($V_{\rm DS}$); $T_{\rm C}$ = 25 °C; D = 0; parameter: $t_{\rm p}$



4 Max. transient thermal impedance

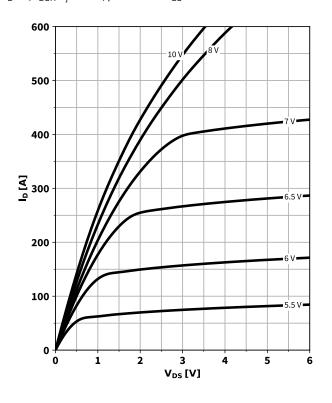
$$Z_{\text{thJC}} = f(t_p)$$
; parameter: D = t_p/T





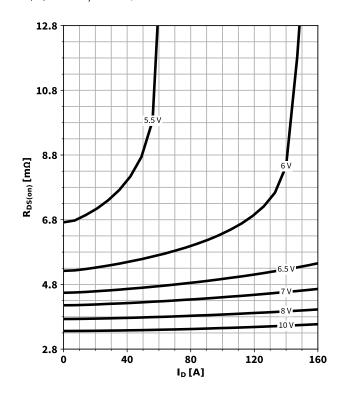
5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 \,^{\circ}\text{C}; \text{ parameter: } V_{GS}$



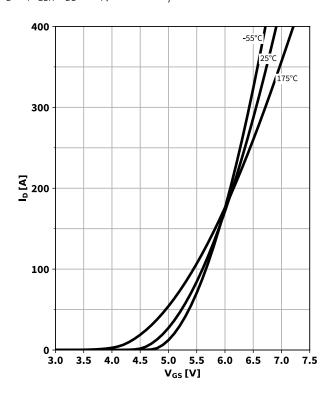
6 Typ. drain-source on-state resistance

 $R_{\mathrm{DS(on)}} = \mathrm{f}(I_{\mathrm{D}}); T_{\mathrm{j}} = 25 \, ^{\circ}\mathrm{C}; \mathrm{parameter}: V_{\mathrm{GS}}$



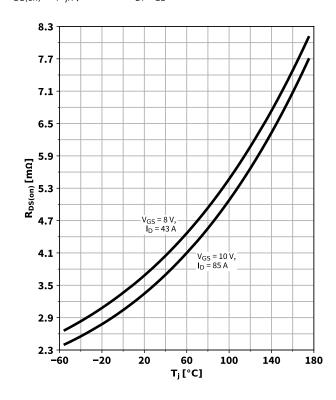
7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 6 \text{ V}; \text{ parameter: } T_j$



8 Typ. drain-source on-state resistance

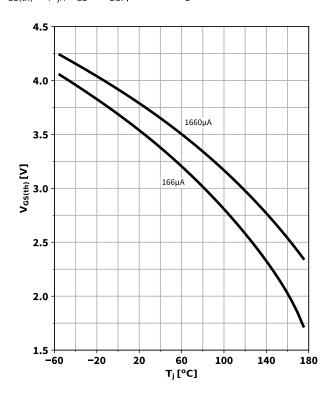
 $R_{DS(on)} = f(T_j)$; parameter: I_D , V_{GS}





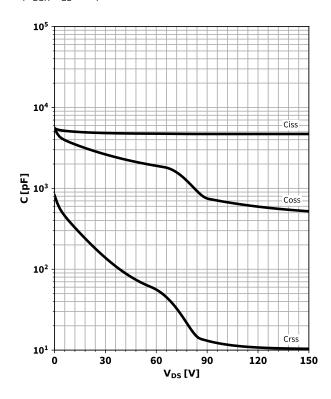
9 Typ. gate threshold voltage

 $V_{\text{GS(th)}} = f(T_{\text{j}}); V_{\text{GS}} = V_{\text{DS}}; \text{ parameter: } I_{\text{D}}$



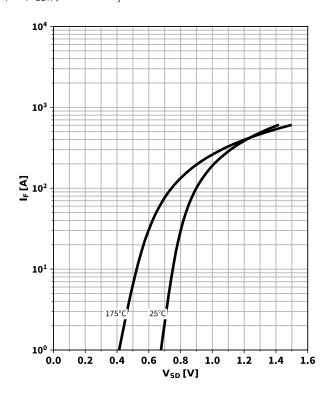
10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$



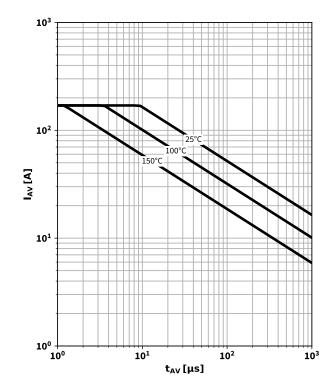
11 Typ. forward diode characteristics

 $I_F = f(V_{SD})$; parameter: T_j



12 Typ. avalanche characteristics

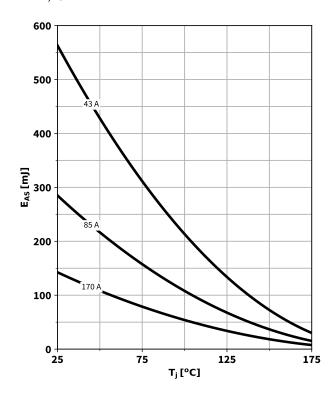
 $I_{AS} = f(t_{AV})$; parameter: $T_{j(start)}$





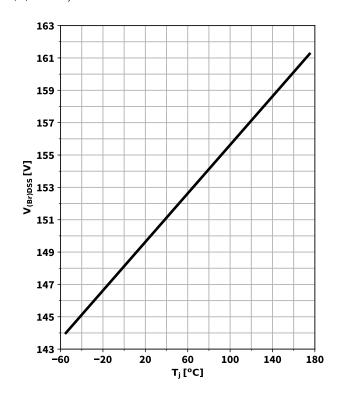
13 Typical avalanche energy

 $E_{AS} = f(T_j)$; parameter: I_D



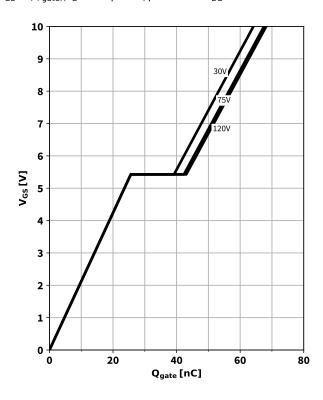
14 Drain-source breakdown voltage

 $V_{(Br)DSS} = f(T_j); I_D = 10 \text{ mA}$

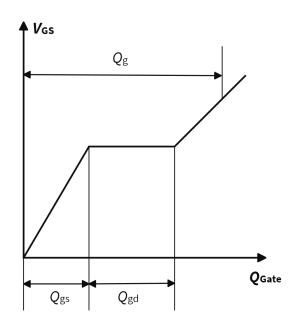


15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 85 \text{ A pulsed}; parameter: } V_{DD}$



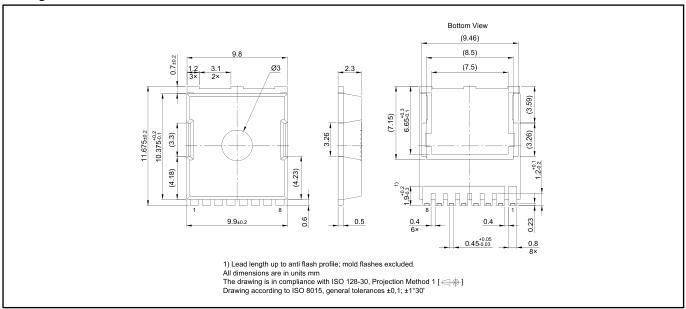
16 Gate charge waveforms



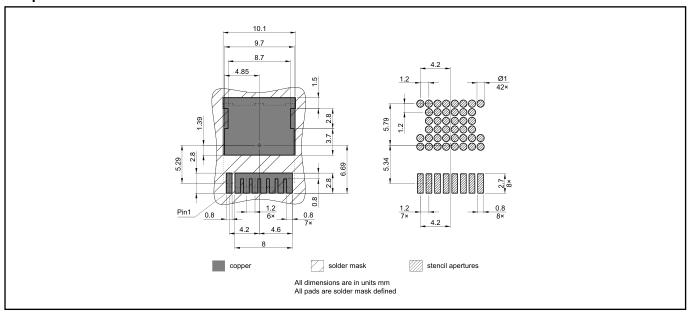
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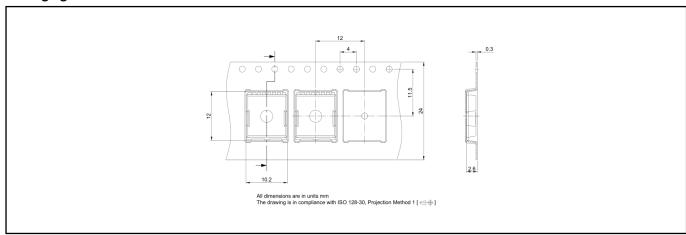
Package Outline



Footprint



Packaging



IAUTN15S6N038



Revision History

Revision	Date	Changes
Revision 1.0	30.04.2025	Final data sheet

Trademarks

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